



<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10724907</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>SEIVER, JOHN R.</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
174	70B	09/25/2006	HK
174	71B	09/25/2006	HK
174	72B	09/25/2006	HK
174	99B	09/25/2006	HK

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Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10724907	SEIVER, JOHN R.
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
62/612 (consulted William Doerrier)	09/04/2006	HK
174/70B,71B,72B,99B (consulted Chao Nguyen)	08/31/2006	HK
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